

# aim:

validation of the concept of a Selene-type reflectometer and checking the McStas simulations thereon the prototype will be used to investigate the various operation modes

# set-up:

the prototype will be setup on the instrument BOA

- the distance between initial slit and sample is 4 m
- $\circ$  the total space available is 9.1 m
- 3 m between sample and detector to obtain a sufficient resolution
- horizontal and vertical geometry are identical
- the geometry allows for
- -3Å  $< \lambda < 10$ Å
- $-\Delta\theta = 1.8^{\circ}$

# time-line:

- operational mid of August 2012
- firs tests (unpolarised, RT) in August and September 2012
- modificatios / extention of flecibility (polarisation, sample environment, vertical scattering geometry)
- future tests
- horizontal surfaces
- in-situ sample preparation

# **BOA**:

BOA is a multi-purpose neutron beamline at SINQ, PSI, Switzerland. The operation of BOA (Beamline for neutron Optics and other Approaches) has started successfully in May 2011. The beamline offers the following properties:

- cold source:  $\lambda_{peak} = 3.2 \text{ Å}$
- mean flux (at x = 0):  $1.1 \times 10^8 \,\mathrm{n \, s^{-1} cm^{-2} m A^{-1}}$
- wavelength band: 1.5 Å 15 Å
- cross section:  $40 \text{ mm} \times 150 \text{ mm}$
- variable instrument length: 9.5 m (extendable to 12 m)
- polarization:
- primary polarization: permanent 1.6m long bender unit (FeCoV/TiN)
- polarization analyzer:  $4^{\circ}$  bender unit (FeCoV/TiN)
- spin flipper: adiabatic spin flipper
- detectors:
- single <sup>3</sup>He detector
- <sup>3</sup>He x y (EMBL wire) 172 $mm \times 190mm$ , resolution  $\approx 2mm$
- CCD camera (Andor IKON-M) 1024  $\times$  1024 pixel, resolution < 40 $\mu$ m
- options:
- time of fligth measurements
- monochromatic measurements (using a douple monochromator setup)

more details see <a href="http://www.psi.ch/sinq/boa/description">http://www.psi.ch/sinq/boa/description</a>

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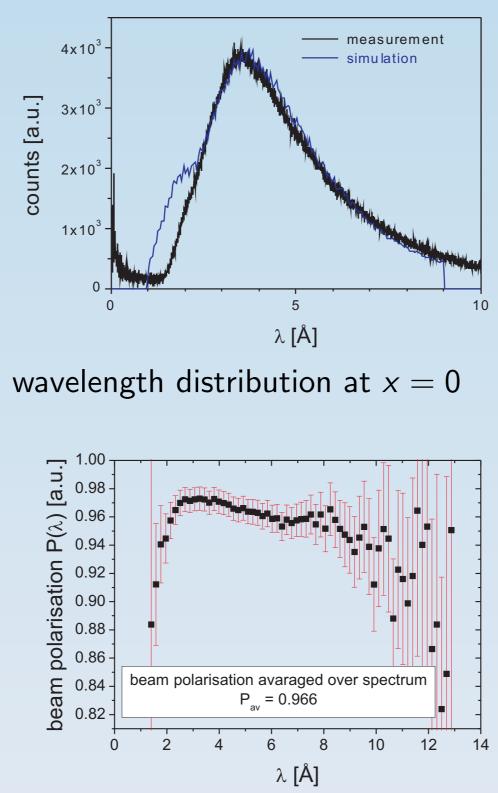
# Selene-type reflectometer

## components:

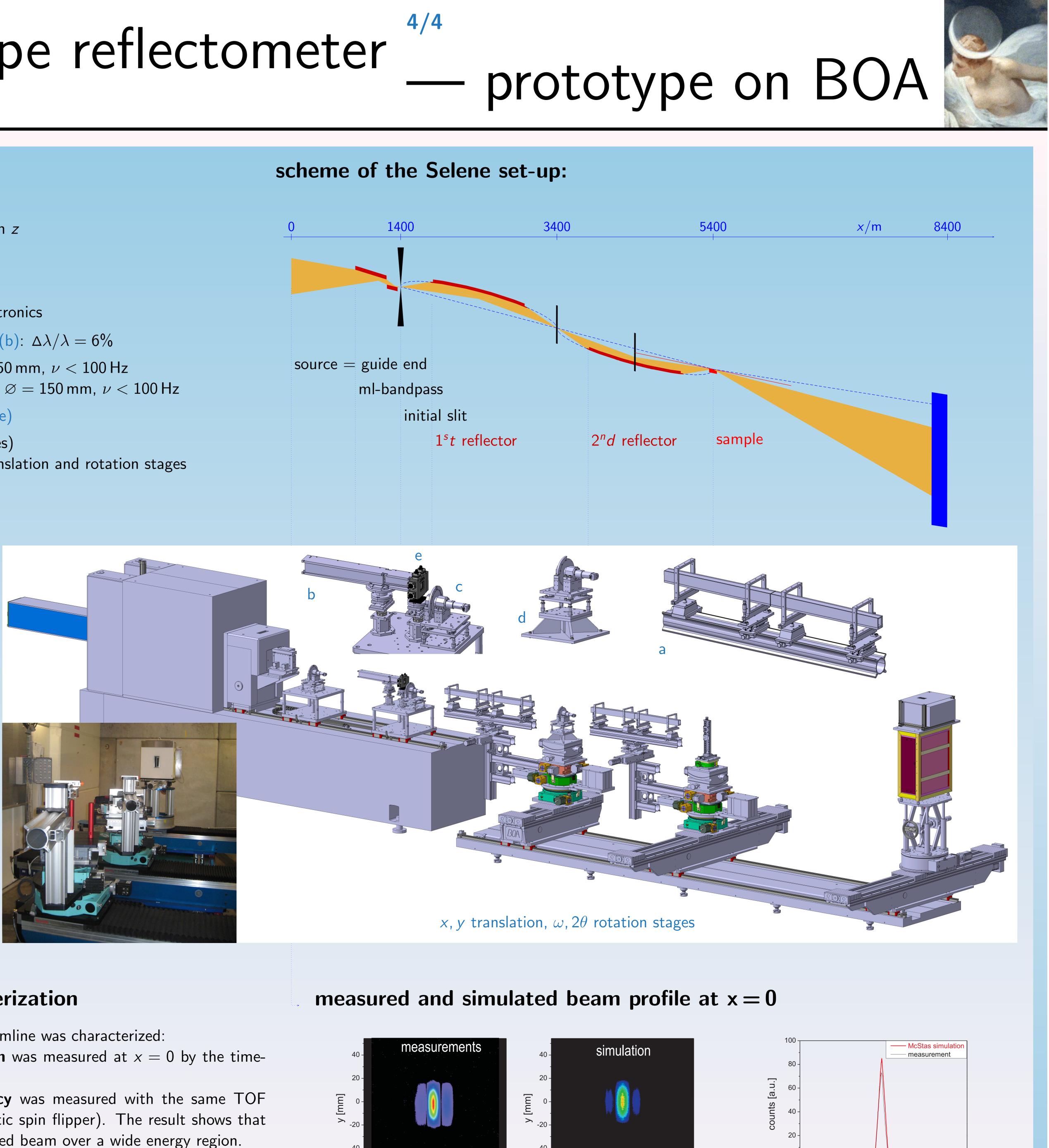
# $\circ$ 2 guides (a):

- elliptic reflectors in y and in zfocal point distance: 2 m lengths: 1.2 m coating: NiTi, m = 5manufactored by SwissNeutronics
- $\circ$  multilayer monochromator (b):  $\Delta\lambda/\lambda = 6\%$
- $\circ$  source chopper (c):  $\varnothing = 150 \,\mathrm{mm}, \,\nu < 100 \,\mathrm{Hz}$
- $\circ$  frame-overlap chopper (d):  $\varnothing = 150$  mm,  $\nu < 100$  Hz
- high-precision (X-ray) slit (e)
- support frames (X95 profiles)
- manual and automated translation and rotation stages

### instrument lay-out:



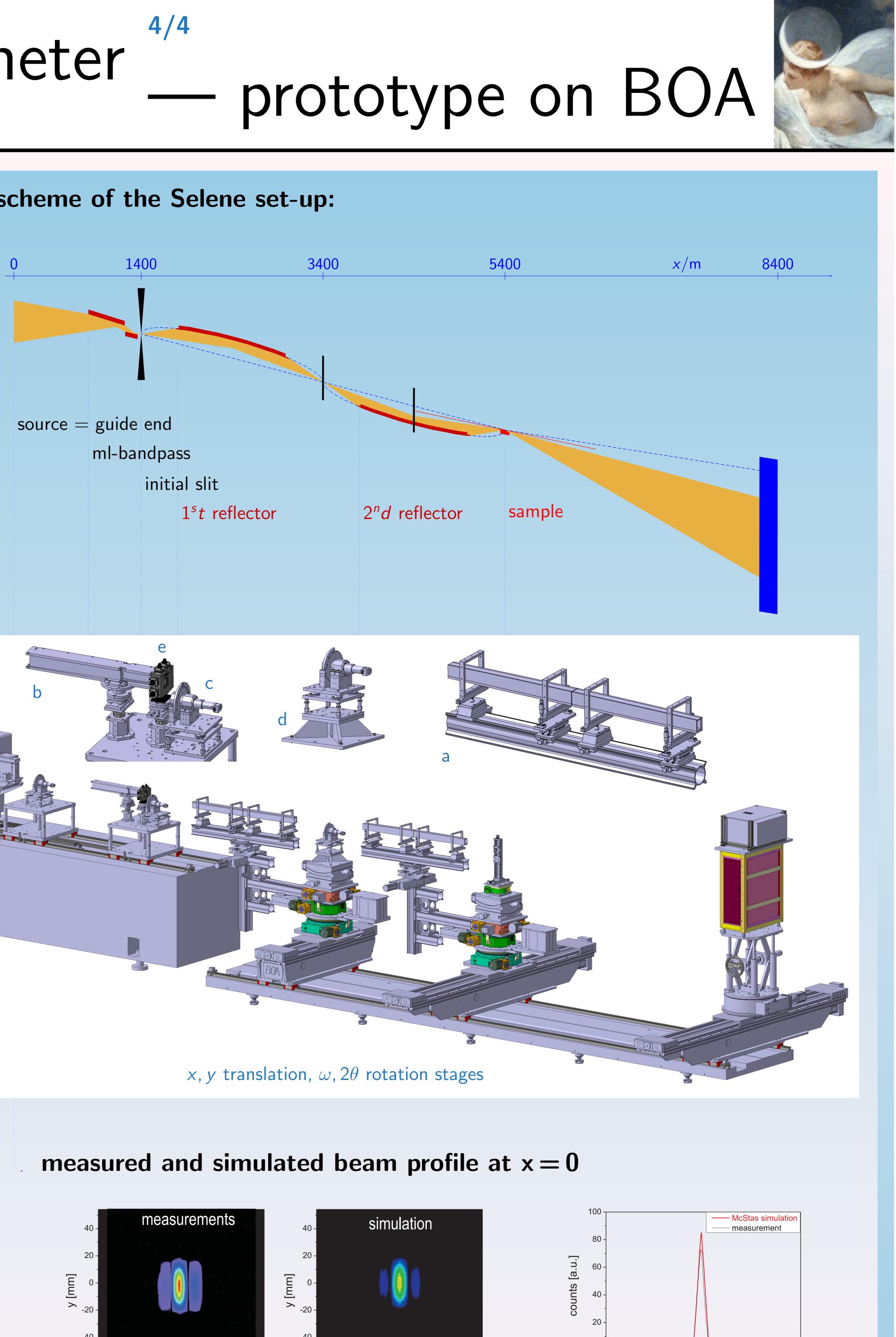
polarization efficiency at x = 0

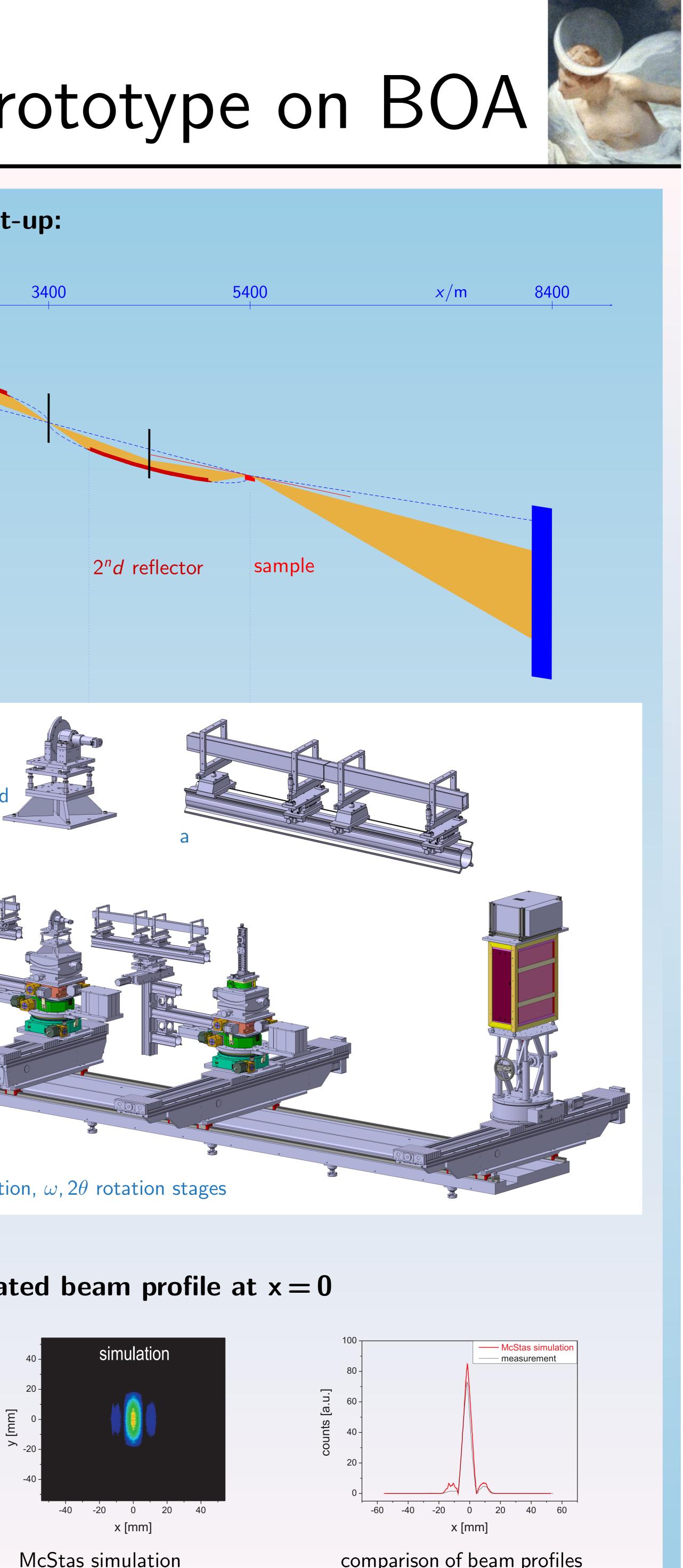


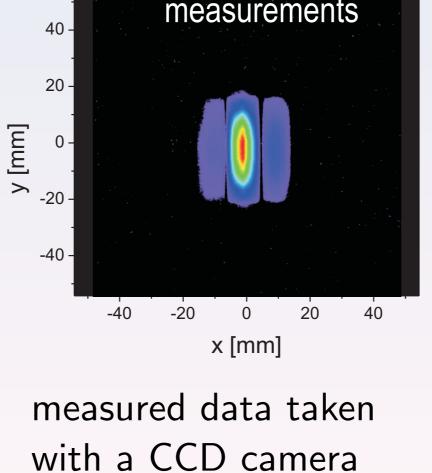
# **BOA** beam characterization

In the start-up phase the beamline was characterized:

- The wavelength spectrum was measured at x = 0 by the timeof-flight technique.
- The **polarization efficiency** was measured with the same TOF setup (including an adiabatic spin flipper). The result shows that BOA offers a highly polarized beam over a wide energy region.
- The **beam profiles** have been measured at different positions along the neutron flight path (x-axis). The relevant measurement/simulation for the *Selene* setup is shown on the right.
- The performed **McStas simulation** for this setup shows a good agreement.







comparison of beam profiles (integrated data over y)